


<b>Search Notes</b> 	<b>Application/Control No.</b> 10668974	<b>Applicant(s)/Patent Under Reexamination</b> SHIMIZU ET AL.
	<b>Examiner</b> Jacob, Mary C	<b>Art Unit</b> 2123

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
703	14	12/26/06	MCJ

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Updated Inventor Search: East, Google Scholar, IEEE	12/26/06	MCJ
Updated Assignee Name Search: East, Google Scholar	12/26/06	MCJ
Updated East Search: see search history	12/7/06	MCJ
IEEE diffusion size and simulate and isolation; diffusion length and simulation and isolation and parameter; Updated Inventor Name Search: shimizu t, and diffusion, sakamoto h. and diffusion	12/7/06	MCJ
Google Scholar: "diffusion size" isolation; "diffusion size" parameter simulation	12/7/06	MCJ
Talked to Paul Rodriguez, SPE AU2123 about allowability of claims	12/7/06	MCJ
Consulted with Kakali Chaki, QAS TC2100 about 101 issues	12/12/06, 12/21/06	MCJ

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	PG PUB Text Search: See EAST Search History for Interference Search	12/26/06	MCJ